Notic of Ref rences Cited

| Application/Control No. | Applicant(s) | Patent Under | |
|-------------------------|---------------------------------|--------------|--|
| 10/002,779 | Reexamination AGARWAL ET AL. | | |
| Examiner | Art Unit | | |
| DAVID VU | 2818 | Page 1 of 1 | |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Bate MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------------|----------------|
| * | Α | US-6,409,904 | 06-2002 | Uzoh et al. | 205/137 |
| * | В | US-6,365,502 | 04-2002 | Paranjpe et al. | 438/622 |
| * | С | US-4,851,895 | 07-1989 | Green et al. | 257/751 |
| * | D | US-5,109,238 | 04-1992 | Watanabe et al. | 347/204 |
| * | Ε | US-4,564,702 | 01-1986 | Wennerberg, Arnold N. | 562/493 |
| | F | US- | | | |
| | G | US- | | | |
| | Н | US- | | | |
| | ı | US- | | | |
| | J | US- | | | |
| | К | US- | | | |
| | L | US- | | | |
| | М | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
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| | 0 | | | | | |
| | Р | , | | | | |
| | Q | | | | | |
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| | s | | | | | |
| | Т | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | | | |
|---|---|---|--|--|--|
| | U | | | | |
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| | w | | | | |
| | x | | | | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.